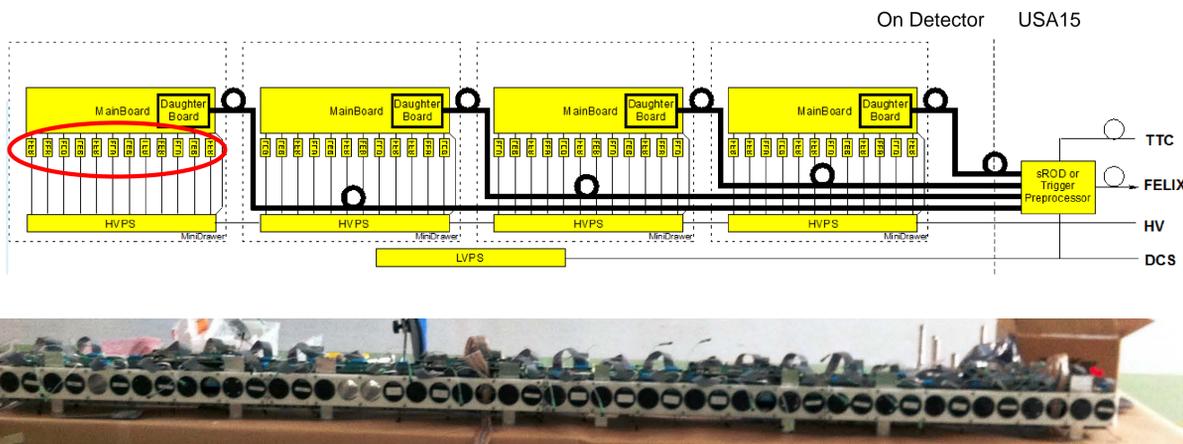


## The TileCal Upgrade Readout Architecture

- Prototype Development Program for the Phase 2 Upgrade
- Replacement of All Front-End & Back-End Electronics
- 3 Front-End Technologies being Considered for PMT Readout :
  - 3-in-1 (Discrete Design)
  - FATALIC (Custom ASIC)
  - **QIE: Charge Integrator and Encoder**
    - Custom ASIC, 350 nm SiGe
- ➔ **Designs in Progress**
- ➔ **Test Beam Starting**
- ➔ **Technology Decision: Summer, 2016**



### Front-End Components

- **Front-End Main Board**
  - Analog & Digital
- **Front-End Board**
  - Analog & Digital
- **Daughter Board**
  - Kintex-7 FPGA
- **Optical Link (Luxtera)**
  - Analog & Digital
- **HV Control Board**
  - Analog & Digital
- **Low Voltage Power**
  - Analog & Digital
- **COTS POL Regulators**
  - Analog & Digital

### General Features of the QIE12

– “Current Splitter” with Gated Integrator

- No Pulse Shaping
- Pseudo-Logarithmic Response

– Pipelined Operation;  
Dead-timeless at 40 MHz

– 18-bits Dynamic Range

– 1.5 - 3 fC Least Count

– Internal TDC → 1 ns resolution

– Internal Shunt for External Current Integrator

– Internal Charge Injection

– Low Power – 360 mW/ch (Chip Only)

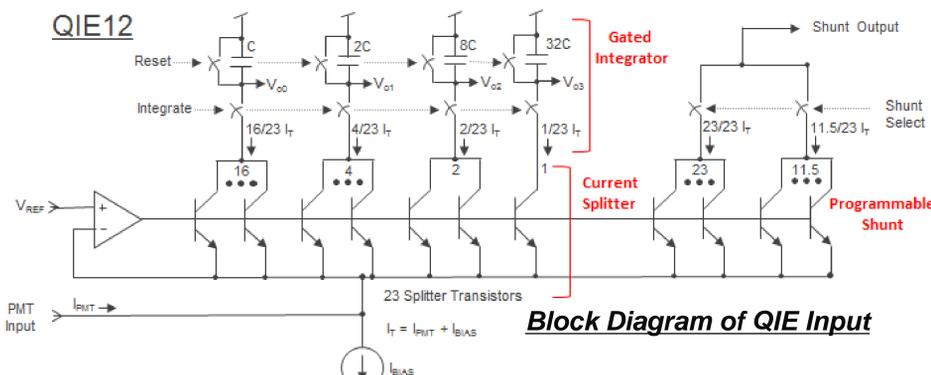
– Highly Integrated; Simple Interface & Support Circuitry → High Reliability

– Radiation Tolerant (SiGe Process for TID; SEU-Tolerant Design)

– 50 Ohm Input, Incorporate SPI for Slow Control

- Allows for one data bus for all slow control functions: Integrator ADC; Q Inj DAC, QIE

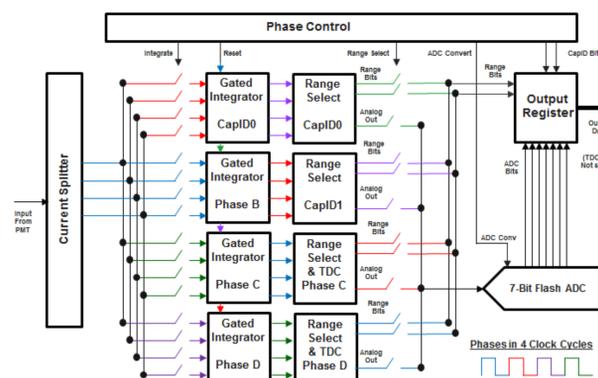
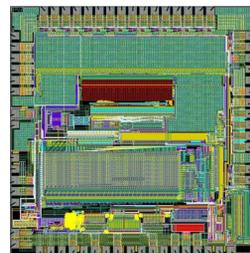
## Overview of the QIE12



Block Diagram of QIE Input

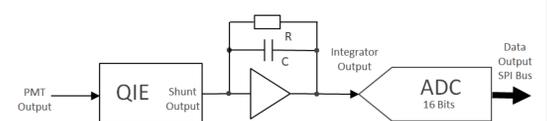
### Pipelined Operation

### QIE12 Chip layout

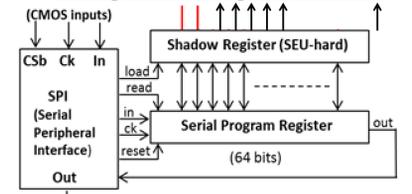


### Current Integrator Implementation

(External to Chip)

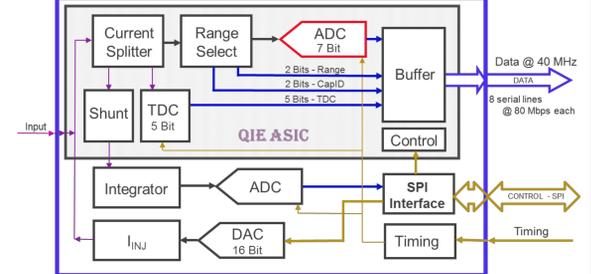


### Programming Interface



### Block Diagram of QIE Front-End Board

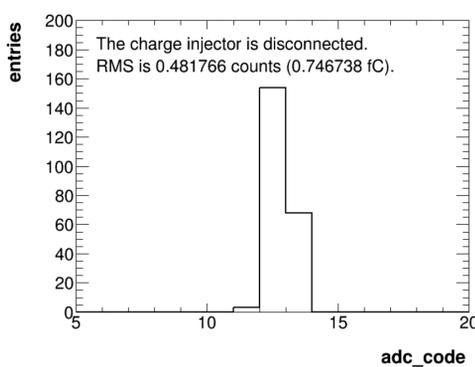
(Design in progress...)



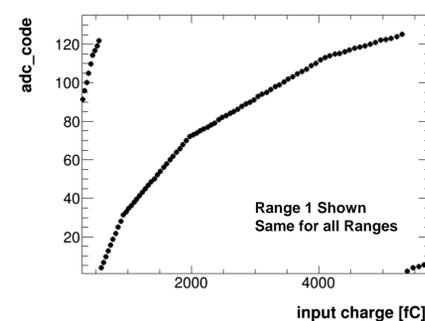
- ➔ **Simple Front-End**
- ➔ **Goal: Robust; High Reliability**

## A Few Measurements & Results on Prototype Chips

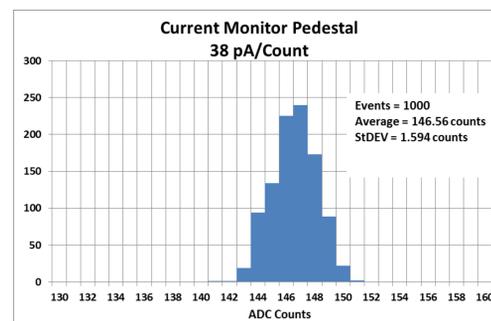
### Pedestal Noise



### ADC Transfer Function

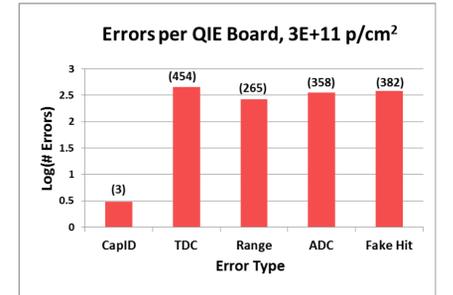


### DC Current Monitor

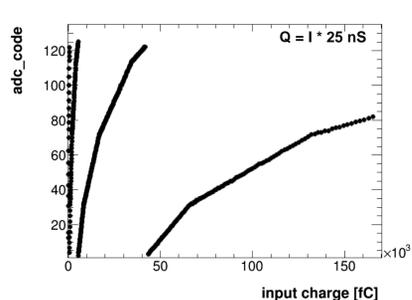


### Current SEE Performance

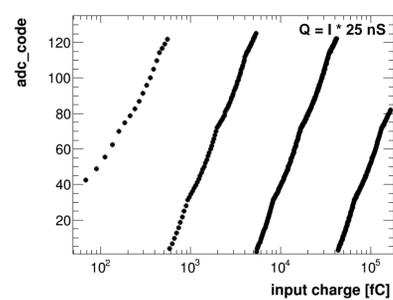
~ 1 SEU Error per 3E+8 p/cm<sup>2</sup> per chip  
~ 1 Fake Hit per 1E+9 p/cm<sup>2</sup> per chip  
No Errors in Shadow Register (SEU-Hard)  
Est 10 yr Dose: ~4E+9 p/cm<sup>2</sup>



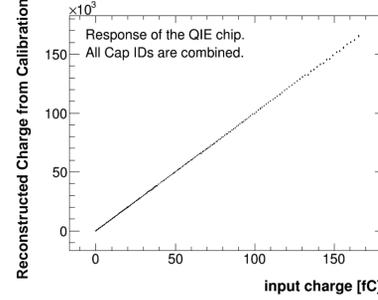
### Current Injection – Linear scale



### Current Injection – Log scale



### Reconstructed Charge



### Linearity Residuals

